

**Testing of ceramic raw and basic materials - Direct determination of mass fractions of impurities in powders and granules of silicon carbide by OES by DC arc excitation**

## EESTI STANDARDI EESSÕNA

## NATIONAL FOREWORD

Käesolev Eesti standard EVS-EN 15979:2011 sisaldab Euroopa standardi EN 15979:2011 ingliskeelset teksti.

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Standard on kättesaadav Eesti standardiorganisatsioonist.

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This standard is ratified with the order of Estonian Centre for Standardisation dated 28.02.2011 and is endorsed with the notification published in the official bulletin of the Estonian national standardisation organisation.

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The standard is available from Estonian standardisation organisation.

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English Version

Testing of ceramic raw and basic materials - Direct  
determination of mass fractions of impurities in powders and  
granules of silicon carbide by OES by DC arc excitation

Essai des matières premières et matériaux de base  
céramiques - Détermination directe des fractions  
massiques d'impuretés dans les poudres et granulés de  
carbure de silicium par OES à l'excitation d'arc DC

Prüfung keramischer Roh- und Werkstoffe - Direkte  
Bestimmung der Massenanteile an Verunreinigungen in  
pulver- und kornförmigem Siliciumcarbid mittels OES und  
Anregung im Gleichstrombogen

This European Standard was approved by CEN on 10 December 2010.

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## Foreword

This document (EN 15979:2011) has been prepared by Technical Committee CEN/TC 187 “Refractory products and materials”, the secretariat of which is held by BSI.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, at the latest by July 2011, and conflicting national standards shall be withdrawn at the latest by July 2011.

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## 1 Scope

This European Standard describes the method for the analysis of mass fractions of the impurities Al, B, Ca, Cr, Cu, Fe, Mg, Ni, Ti, V and Zr in powder- and grain-shaped silicon carbide of ceramic raw and basic materials. This application can also be extended to other metallic elements and other similar non-metallic powder- and grain-shaped materials such as carbides, nitrides, graphite, carbon blacks, cokes, carbon, as well as a number of further oxidic raw and basic materials after appropriate testing.

NOTE There are positive interferences for materials such as e.g. graphite, B<sub>4</sub>C, BN, WC and several refractory metal oxides.

This testing procedure is applicable to mass fractions of the impurities mentioned above from approximately 1 mg/kg up to approximately 3 000 mg/kg, after verification. In some cases it may be possible to extend the range up to 5 000 mg/kg depending on element, wavelength, arc parameter, and sample weight.

## 2 Principle

The combustion and evaporation of the crushed sample material takes place in the arc in an atmosphere of mixed argon and oxygen or in air. The metallic traces in the arc plasma are excited to emission of light. The light is guided into a simultaneous emission spectrometer (e.g. by coupling via fibre-optics or directly). The light is split in its spectral lines and measured by applicable detectors like a photomultiplier, charge coupled device (CCD), and charge injection device (CID). The mass fractions of elements in the sample are calculated by comparison of the intensities of the element-specific spectral line with those of a calibration sample of identical material.

## 3 Spectrometry

The optical emission spectrometry is based on generation of line spectra of excited atoms or ions, in which each spectral line can be definitely related to an element and the line intensities are proportional to the mass fractions of elements in the measured sample (see [6], [7] & [12]).

Contrary to wet-chemical methods via solution the classical sample decomposition is replaced by evaporation and excitation in DC-Arc.

## 4 Apparatus

Ordinary laboratory apparatus and the following:

**4.1 Emission spectrometer**, simultaneous, preferably with time resolved registration of signal, and connected to DC-Arc-equipment.

**4.2 Gas flushing device**, for shielding gas and/or reaction gas of DC-Arc, e.g. gas-mixer with mass-flow controller and Stallwood-jet

NOTE When working with air, the shielding gas unit can be omitted.

**4.3 Tweezers**, self-locking.

**4.4 Balance**, an analytical balance at least capable of reading to the nearest 0,1mg. However, for small weight <10 mg, a five figure balance at least capable of reading to the nearest 0,01 mg shall be used.

**4.5 Pressing tool**, for compacting the sample into the electrode.